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Success Measurement in Corporate Venturing: Integrating Three Decades of Research

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Abstract: Measurement approaches to corporate venturing (CV) success are highly diverse in the extant literature. Furthermore, these approaches rarely build on each other, making it difficult to derive comparable conclusions about CV outcomes. Employing a systematic literature review of three decades of research, the objective of this study is to provide transparency and structure in the broad field of CV research. Subsequently, the paper examines 28 studies in detail, resulting in two main contributions to the research field. First, three structural dimensions of measurement approaches are derived from the studies in the sample, namely, "level of analysis" (parent, program, and venture levels), "measurement perspective" (objective, subjective, and mixed measurement), and "locus of opportunity" (internal, external, and general CV activities). Second, an integrated overview of nine unique clusters structures the different measurement approaches. These clusters allow to encapsulate measurement approaches, but also make visible the approaches' heterogeneity, as well as specific measurement items. Thereby, the study contributes to CV research by revealing and reconciling the variety of CV success-measurement approaches. The study also provides relevant insights for practitioners, by making transparent the various approaches to measuring the success of CV activities and presenting a list of 114 concrete and distinct measurement items.

 $\textbf{Keywords:} \ corporate \ venturing, \ measurement \ items, \ success \ measurement, \ structured \ literature \ review$

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